

## 12500 TI Boulevard, MS 8640, Dallas, Texas 75243

# PCN# 20130723002 TPS40200-Q1 datasheet - CMS C1307014 Information Only

**Date:** 7/25/2013

To: Newark/Farnell PCN

#### Dear Customer:

This is an information-only announcement of a change to a specification for a device that is currently offered by Texas Instruments.

This notification period is per TI's standard process. Any negotiated alternative change requirements will be provided via the customer's defined process. Customers with previously negotiated, special requirements will be handled separately. Any inquiries should be directed to your local Field Sales Representative.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager (PCN www admin team@list.ti.com).

Sincerely,

PCN Team SC Business Services Phone: +1(214) 480-6037 Fax: +1(214) 480-6659

### 20130723002 Attachment: 1

## **Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

**DEVICE** TPS40200QDRQ1 **CUSTOMER PART NUMBER** 

null

Technical details of this Product Change follow on the next page(s).

PCN Number:		201	20130723002					PCN Date:		07/25/2013
Title:	Title: TPS40200-Q1 datasheet - CMS C1307014									
<b>Customer Contact:</b>		PCN Manager		Phone:	+1(214) 480-6037			Dept:	Quality Services	
Change Type:										
Assembly Site				Assembly Process				Assembly Materials		
Design			_	Electrical Specification				Mechanical Specification		
Test Site			_	Packing/Shipping/Labeling				Test Process		
Wafer Bump Site			=	Wafer Bump Material			4	Wafer Bump Process		
Wafer Fab Site			Wafer Fab Materials					Wafer Fab Process		
DCN Details										
PCN Details Description of Change:										
•										
Texas Instruments publication SLUS739 has changed as described below:										
Changes from Revision D (July 2011) to Revision E:										
Changes from Revision D (July 2011) to Revision L.										
Page 3, Deleted T <sub>A</sub> test condition and values from Feedback voltage parameter in ELECTRICAL							ELECTRICAL			
CHARACTERISTICS table										
Reason for Change:										
Remove redundant test condition.										
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):										
No anticipated impact. This is a specification change announcement only. There are no changes to the actual device.										
Changes to product identification resulting from this PCN:										
None										
Product Affected:										
	TPS40200QDRQ1									
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For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com